

IFW

Docket Number: 081468-0304253

PATENT APPLICATION

Client Reference: P-1696.000-US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Reply, the Application of

THEODORE A. PAXTON et al.

Group Art Unit: 2857

Application No.: 10/663,904

Examiner: NOT ASSIGNED

Filed: September 17, 2003

Confirmation No.: 2629

For: ADAPTIVE LITHOGRAPHIC CRITICAL DIMENSION ENHANCEMENT

November 17, 2004

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR 1.56, the attention of the Patent and Trademark Office is hereby directed to the reference listed on the attached PTO-1449. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference be made of record therein and appear among the "References Cited" on any patent to issue therefrom. Applicants respectfully request the Examiner return an initialed copy of the enclosed Form PTO-1449 to Applicants with the next Office communication to indicate that the reference(s) has been considered, per MPEP § 609.

This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of the first Office Action on the merits in the present application. No certification or fee is required.

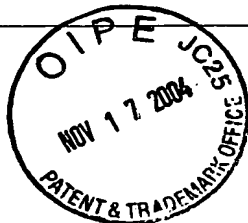
Respectfully submitted,

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Atty.  
Dkt. No.

M#

Client Ref.

304253

P-1696.010-US

# **INFORMATION DISCLOSURE STATEMENT BY APPLICANT**

Applicant: PAXTON et al.

Appln. No.: 10/663,904

Filing Date: September 17, 2003

Date: November 17, 2004

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of

1

Examiner: UNASSIGNED

Group Art Unit: 2857

## **U.S. PATENT DOCUMENTS**

Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
	AR						
	BR						
	CR						
	DR						
	ER						
	FR						
	GR						
	HR						
	IR						
	JR						
	KR						
	LR						

## **FOREIGN PATENT DOCUMENTS**

							Abstract		Readily Available	
		Document Number	Date MM/YYYY	Country	Inventor Name		Enclosed	No	Enclose	No
	MR									
	NR									
	OR									
	PR									
	QR									
	RR									
	SR									
	TR									

## **OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)**

	UR	D.G. Flagello et al., "Understanding Systematic and Random CD variations using Predictive Modelling Techniques," <i>SPIE</i> , Vol. 3679, pp. 162-175.			
	VR				
	WR				
	XR				
	YR				
	ZR				

Examiner

Date Considered:

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.